Semi Design Presents...



CMOS Fabrication Process [p-well method]



Fig. (1) Pure Si single crystal

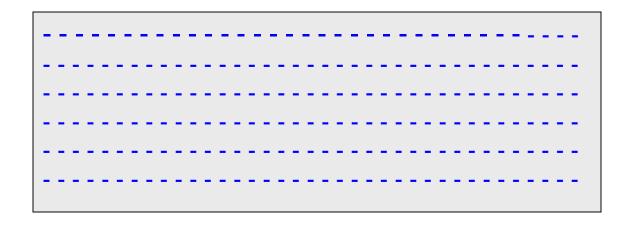


Fig. (2) n-type impurity is lightly doped

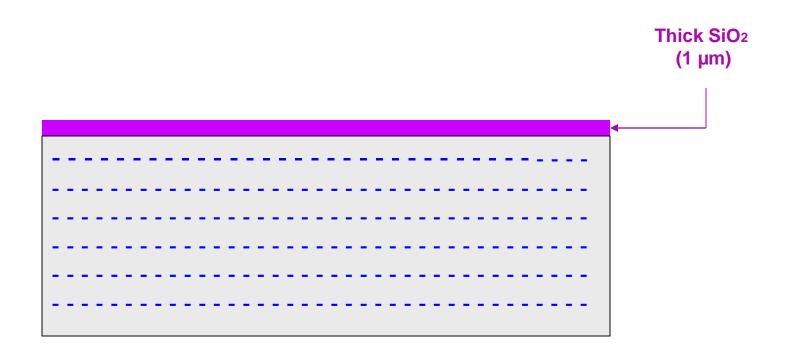


Fig. (3) SiO₂ Deposited over si surface

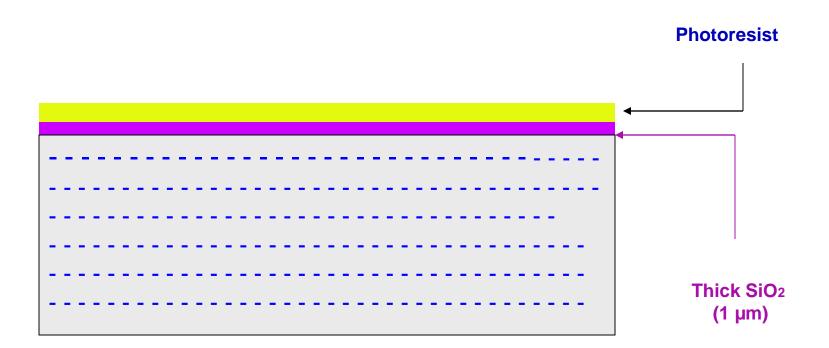


Fig. (4) Photoresist is Deposited over siO2 surface

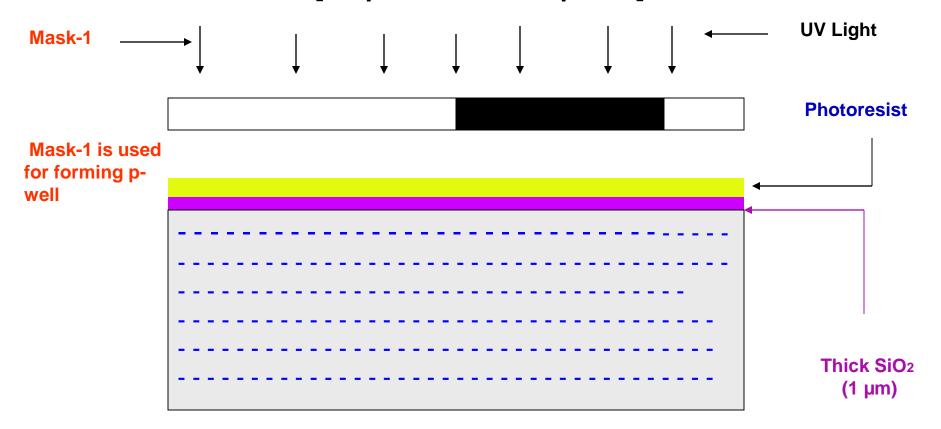


Fig. (5) Photoresist is Deposited over siO2 surface

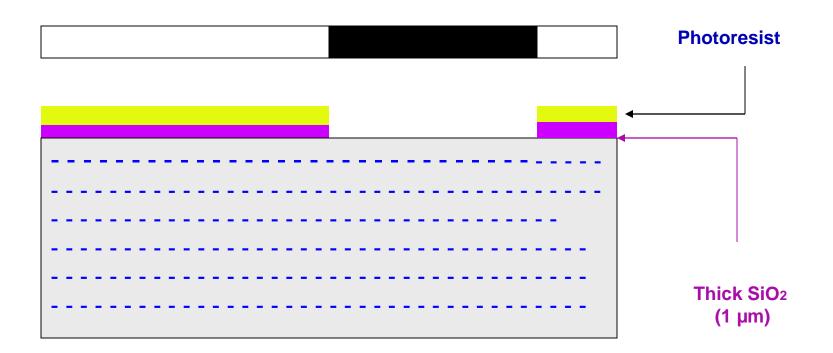


Fig. (6) Photoresist and SiO2 which is not exposed is etched away.



Fig. (7) Hardened Photoresist is stripped away and p-type impurity is added by diffusion process.

N-MOS Fabrication Process [Step- formation of Diffusion area for p-MOS]

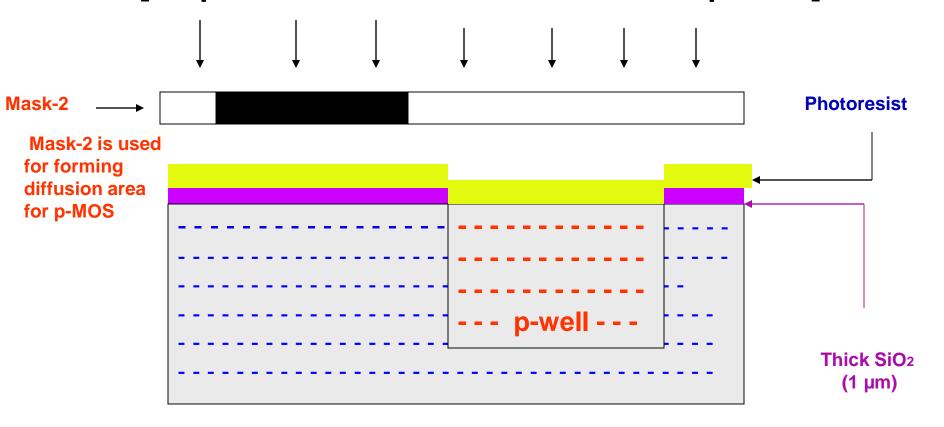


Fig. (8) Photo resist is grown and exposed in UV Light.

N-MOS Fabrication Process [Step- formation of Diffusion area for p-MOS]



Fig. (9) Photoresist and SiO₂ which are un-exposed are etched away.

N-MOS Fabrication Process [Step- formation of Diffusion area for p-MOS]

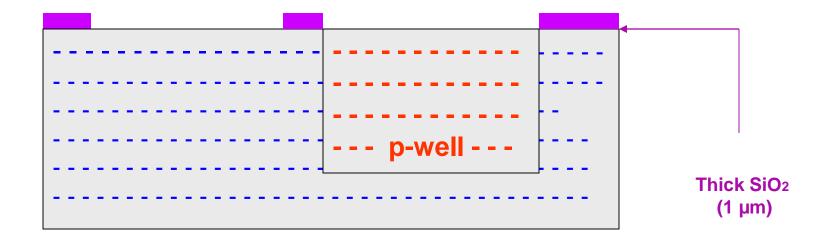


Fig. (10) Polymerised Photoresist is stripped away.

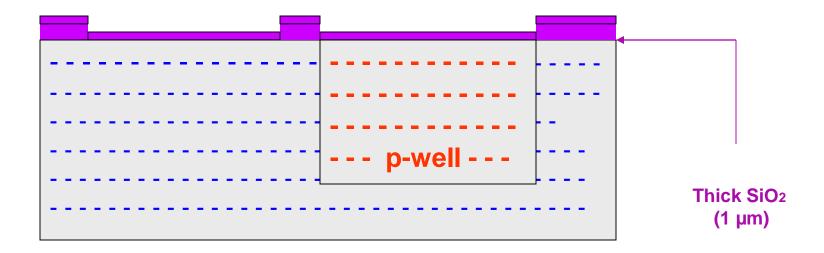


Fig. (11) Deposit Thinox

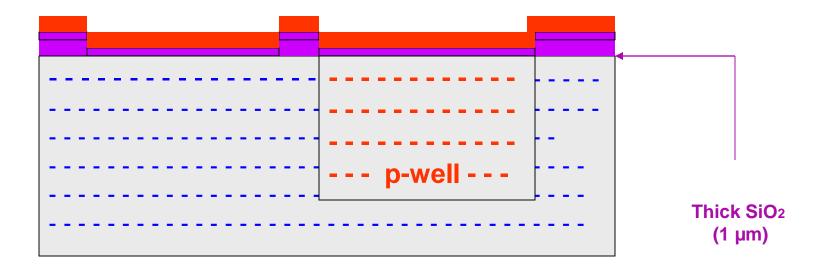


Fig. (12) Deposit Polysilicon

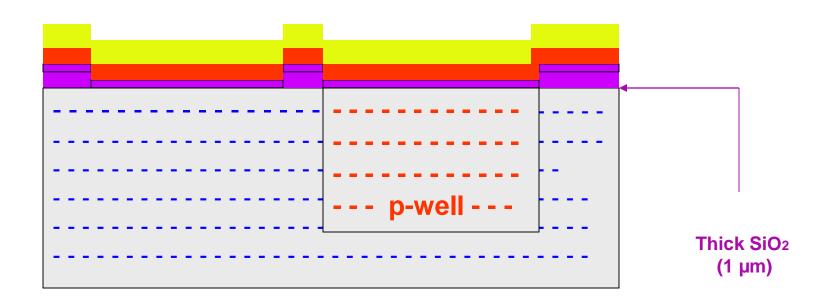


Fig. (13) Deposit Photoresist

[Step- Gate formation for n-MOS and p-MOS]

Mask-3 is used for the formation of Two GATEs

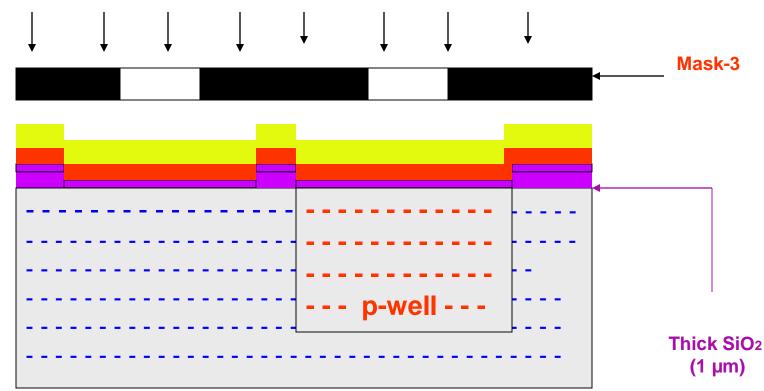


Fig. (14) UV Light Exposure to form GATEs of P-MOS and n-MOS

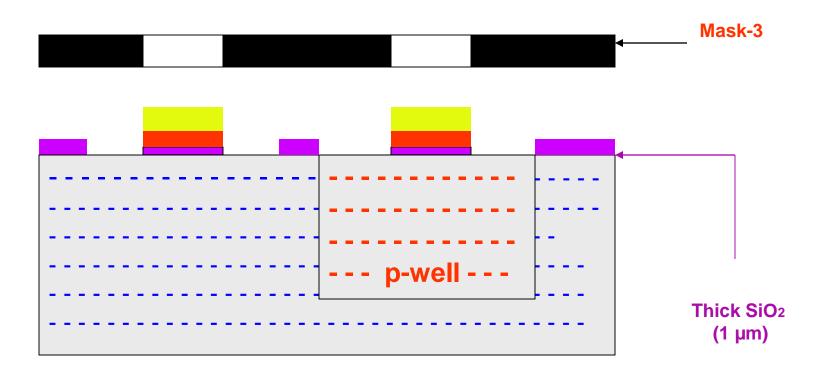


Fig. (15) Un-Exposed Photoresist, Metal and Thinox is etched away.

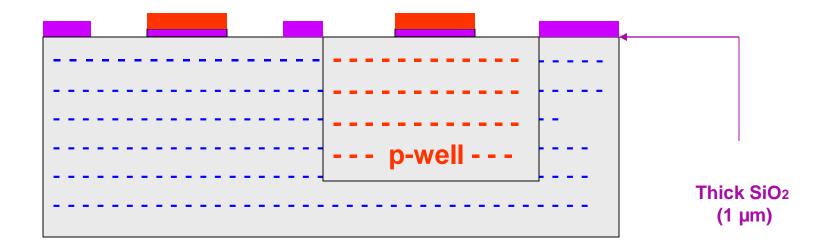


Fig. (16) Polymerised Photoresist is stripped away.

[Step- Source & Drain formation for p-MOS]

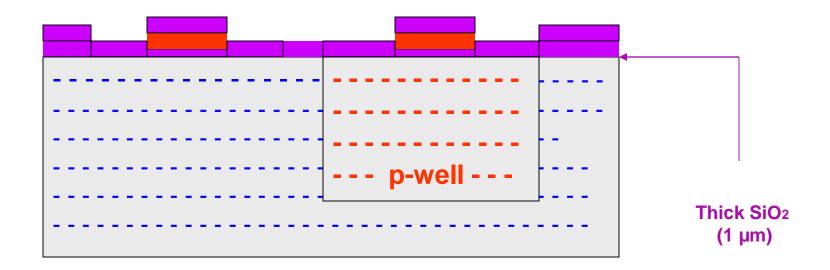


Fig. (17) Grow SiO₂ Layer

[Step- Source & Drain formation for p-MOS]

Mask-4 is used for the formation of S and D of p-MOS

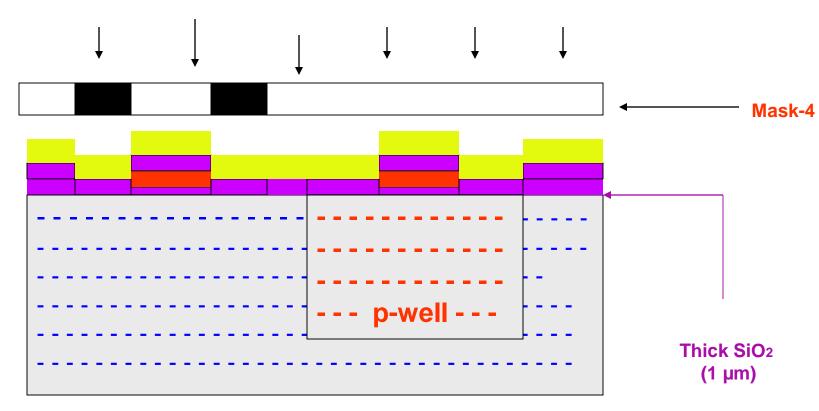


Fig. (18) Grow Photoresist Layer

[Step- Source & Drain formation for p-MOS]

Mask-4 is used for the formation of S and D of p-MOS

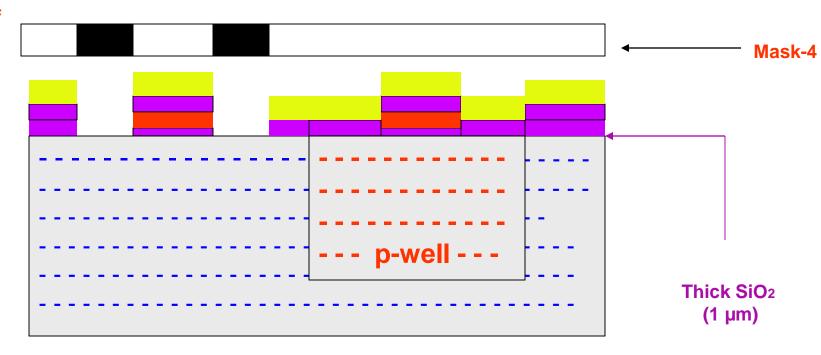


Fig. (19) Etching of un[polymerised photoresist and SiO₂ below it

[Step- Source & Drain formation for p-MOS]

Mask-4 is used for the formation of S and D of p-MOS

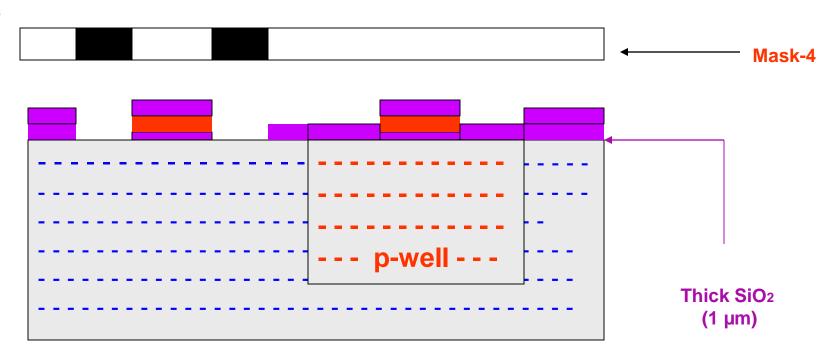


Fig. (20) Strip away hard photoresist

[Step- Source & Drain formation for p-MOS]

Mask-4 is used for the formation of S and D of p-MOS

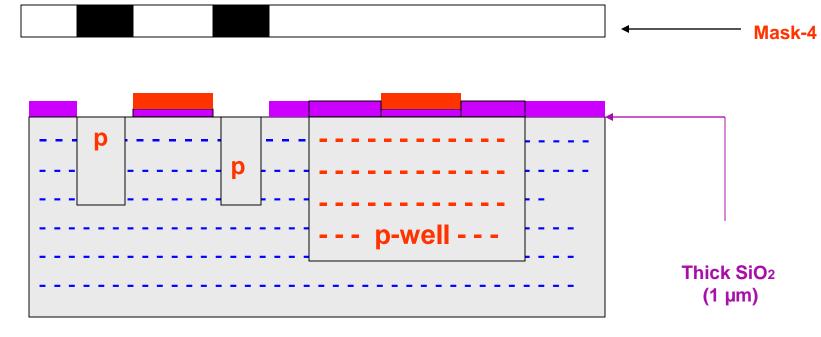


Fig. (21) Diffusion of p-type impurity

[Step- Source & Drain formation for n-MOS]

Mask-5 is used for the formation of S and D of n-MOS

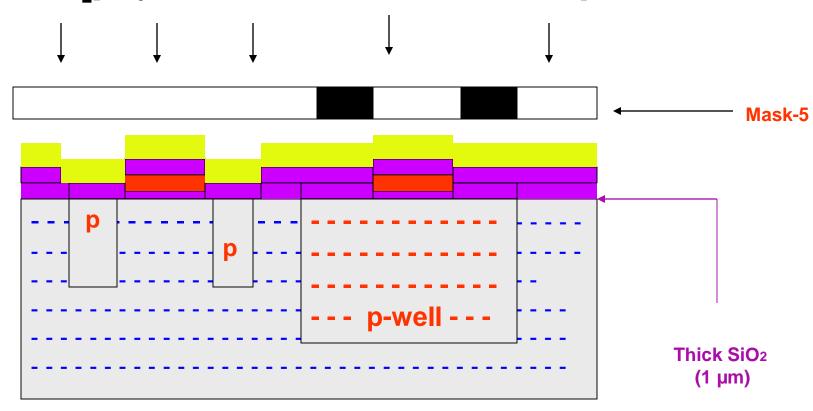


Fig. (22) Grow photoresist

[Step- Source & Drain formation for n-MOS]

Mask-5 is used for the formation of S and D of n-MOS

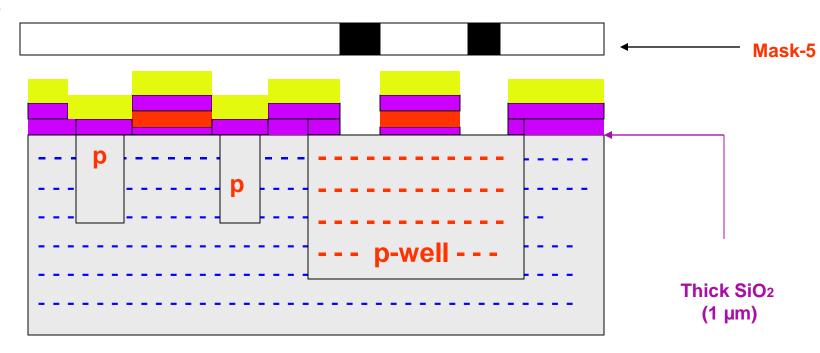


Fig. (23) Etching

[Step- Source & Drain formation for n-MOS]

Mask-5 is used for the formation of S and D of n-MOS

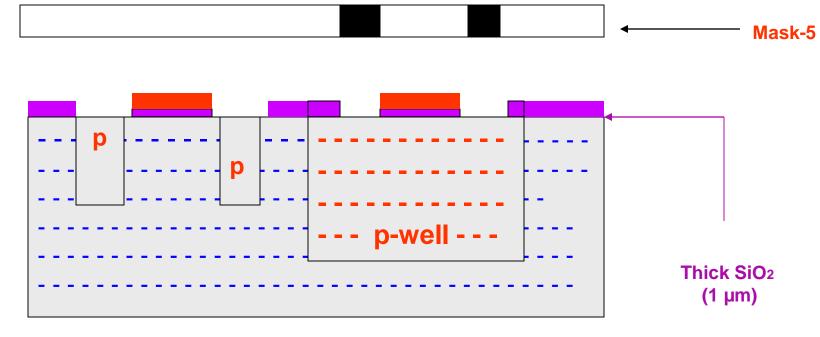


Fig. (24) Hard photoresist stripped away

[Step- Source & Drain formation for n-MOS]

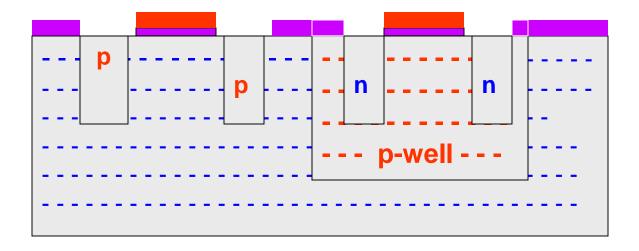
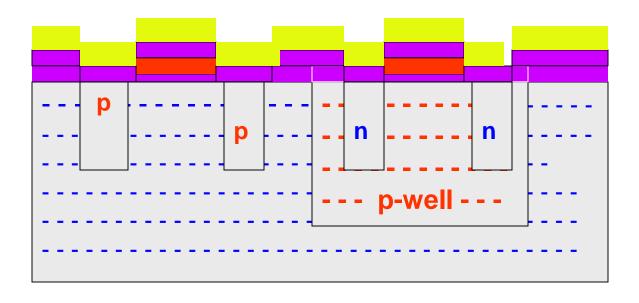


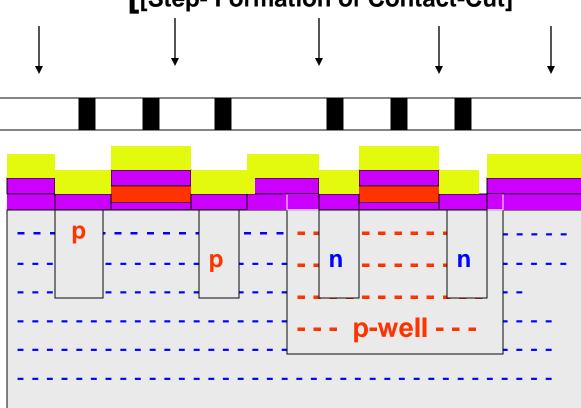
Fig. (25) Diffusion of n-type impurity to form Source and Drain of n-MOS

[Step- Formation of Contact-Cut]



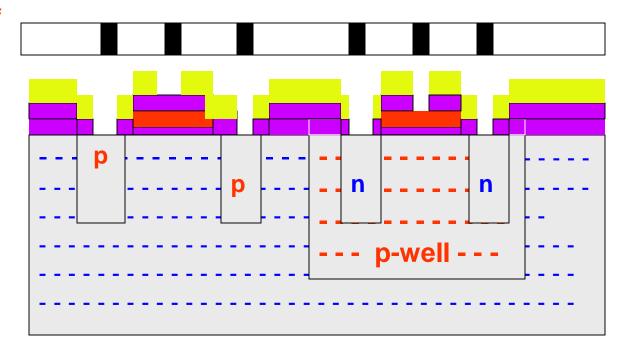
[Step- Formation of Contact-Cut]

Mask-6 is used for the formation of Contact -Cuts in S, D and G of n-MOS and p-MOS



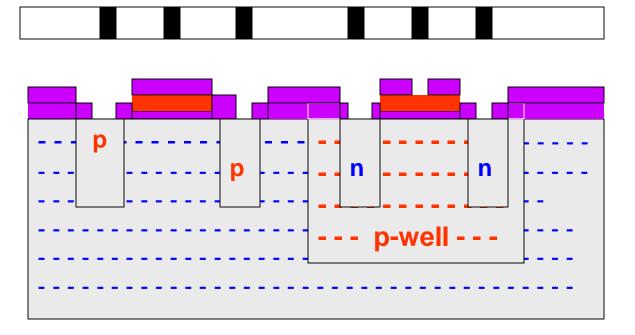
[Step- Formation of Contact-Cut]

Mask-6 is used for the formation of Contact – Cuts in S, D and G of n-MOS and p-MOS

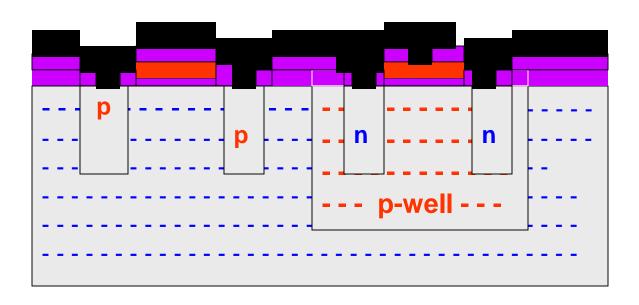


[Step- Formation of Contact-Cut]

Mask-6 is used for the formation of Contact – Cuts in S, D and G of n-MOS and p-MOS



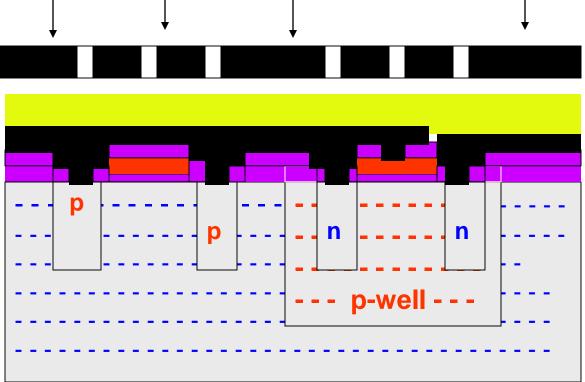
[[Step- Metakkization]



[Step- Metakkization]

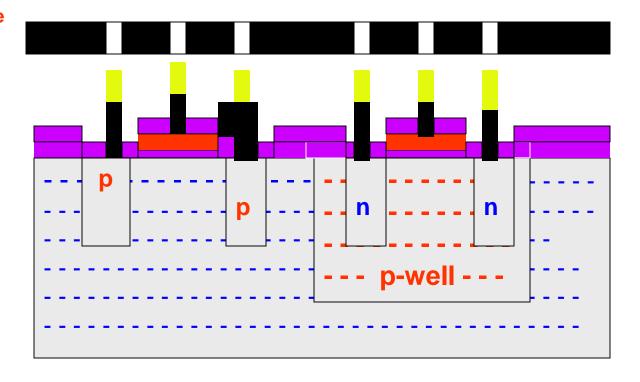
Mask-7 is used for the

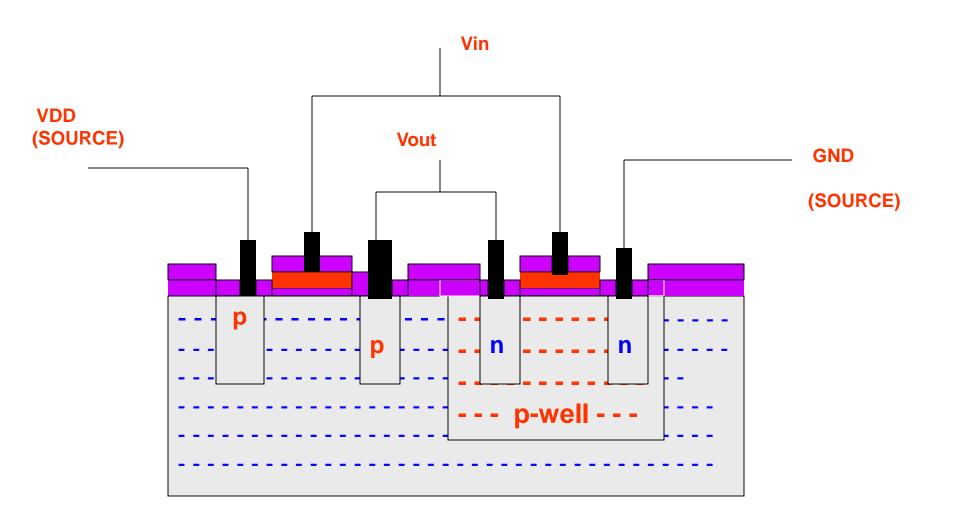
deposition of metal in contact cuts



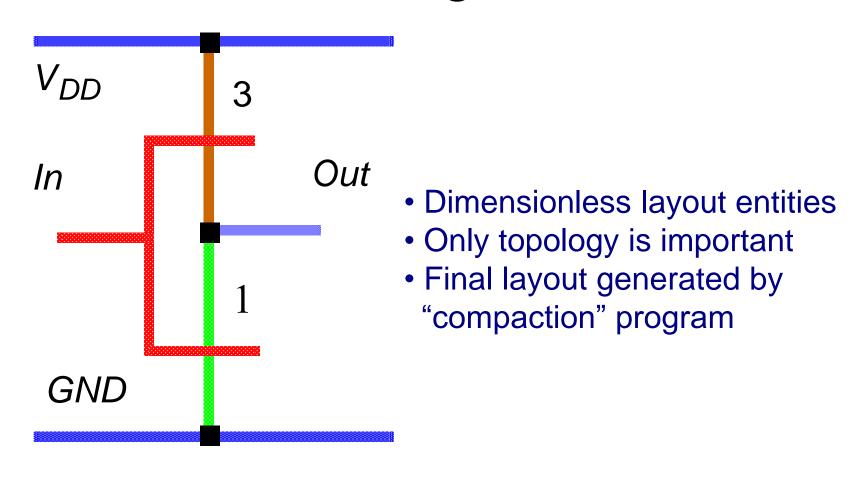
[Step- Metakkization]

Mask-7 is used for the deposition of metal in contact cuts





Sticks Diagram



Stick diagram of inverter

Layout Design

